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David Fofi
Fabrice Meriaudeau
Editors

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Introduction

The 3D Vision research team of the Le2i (Laboratory of Electronics, Computer Science, and Image Processing) is proud to welcome the Eighth International Conference on Quality Control by Artificial Vision to Le Creusot. After having traveled worldwide — the previous editions have been held in Le Creusot in 1993, 1995, 1997 and 2001, in Japan in 1998 and 2005, in Canada in 1999, and in the USA in 2003) — QCAV is back in the city which saw it being born.

Forty-eight papers have been selected by the international scientific committee (among which 12 are for the poster session) from Algeria, Austria, Brazil, Chile, Egypt, France, Iran, Japan, Mexico, Spain, United Kingdom, and United States of America. Moreover, four invited speakers, renowned in the field of image processing and quality control, are honouring us with their presence: Jeffery Price and Kenneth Tobin from the Oak Ridge National Laboratory (USA), Paul O'Leary from the Institute of Automation (Austria); and Frédéric Truchetet from the Le2i, University of Burgundy (France).

It is our pleasure to say that a special section of the *Journal of Electronic Imaging* (co-published by SPIE and IS&T) and a special issue of the *Electronic Letters on Computer Vision and Image Analysis* (edited by CVC Press) will be dedicated to QCAV and will feature selections based on the best papers presented at the conference.

This year's conference is supported by IEEE France Section, SPIE Europe as a cooperating organization, and endorsed by Biomaterials Network. The organizing committee is very grateful to them for trusting us, and would also like to acknowledge our partners and sponsors for their precious help in organizing the conference:

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